Effect of Compiler Optimizations on the Error Resilience of Soft Computing Applications

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Soft Computing Applications

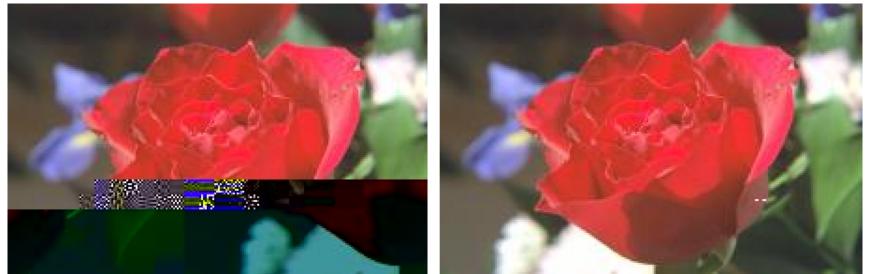
- > Applications in Al, multimedia processing
- > Expected to dominate future workloads [Dubey'07]
- > Tolerate many kinds of faults in data Error Resilient



Original image (left) versus faulty image from JPEG decoder

Egregious Data Corruptions (EDCs)

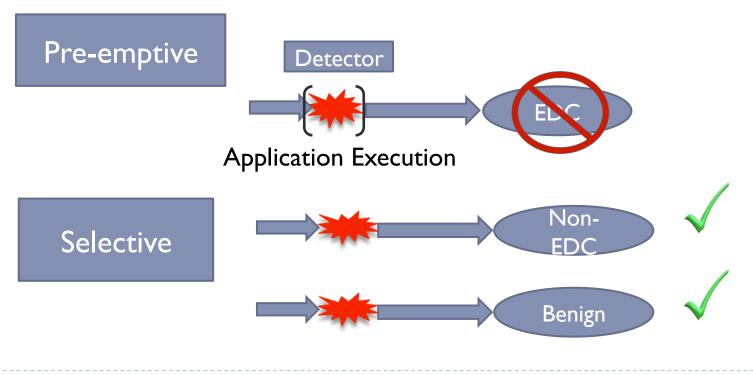
Large or unacceptable deviation in output
Based on fidelity metric (e.g., PSNR < 30)



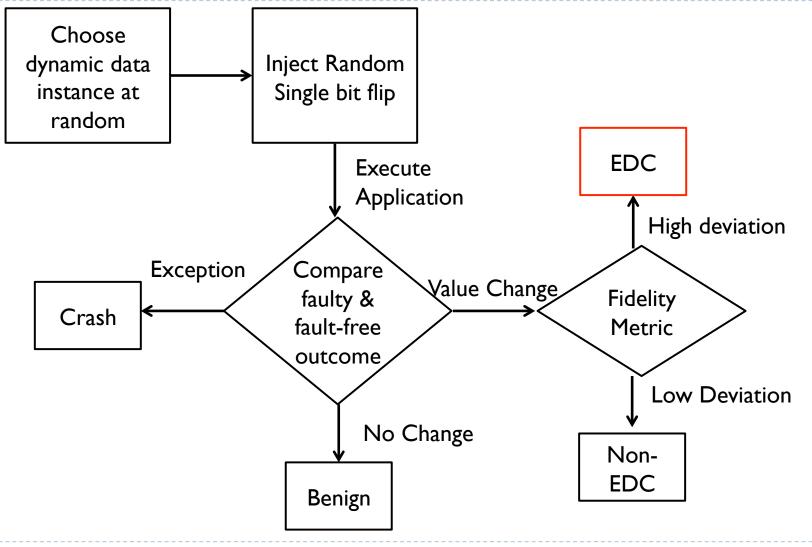
EDC image (PSNR of 11.37) of JPEG vs Non-EDC image (PSNR of 44.79)

Goal

Detect EDC causing faults



Preliminary Fault Injection Study



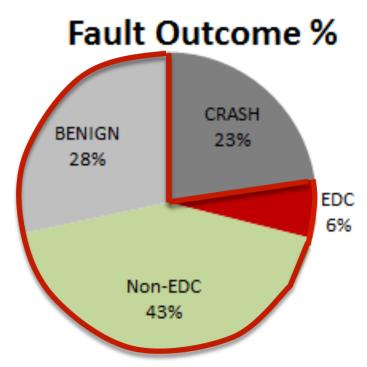
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Why focus on EDC Causing Faults?

> Media-bench programs: Soft-computing applications

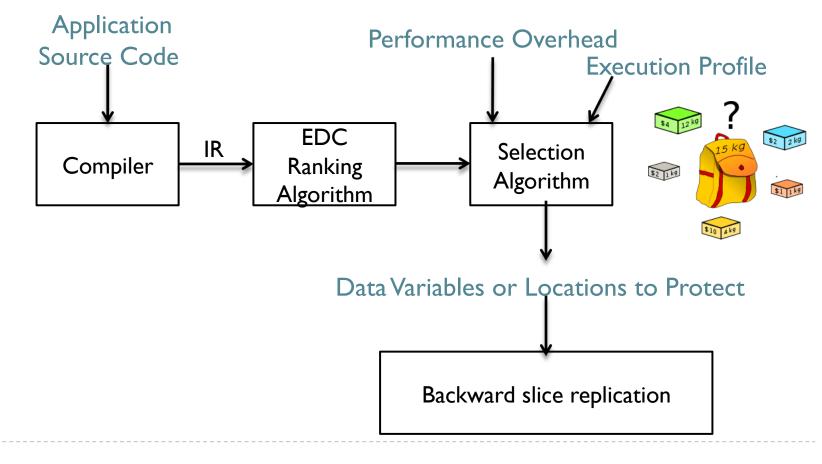
> 92% : tolerable outcomes

Blindly detecting all faults is wasteful !

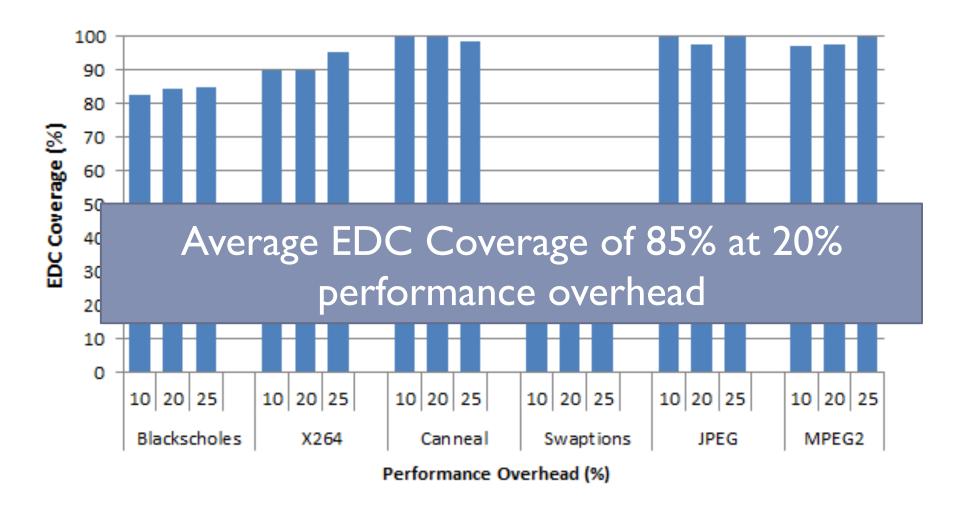


Background

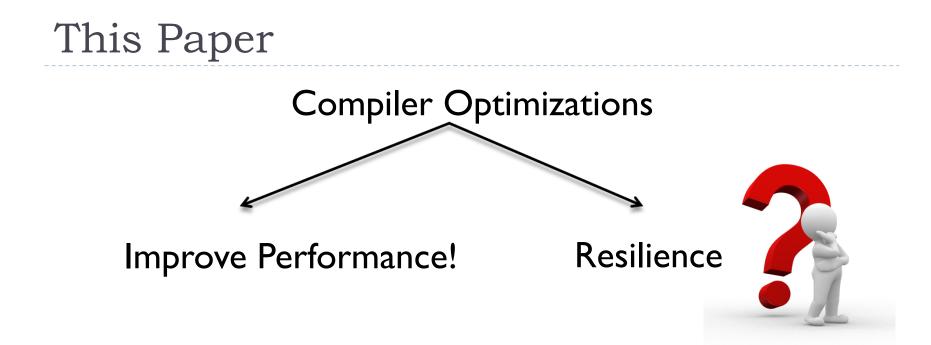
Static analysis algorithm to identify detector locations for EDCs [DSN 2013 – Anna Thomas]



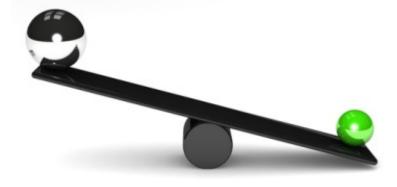
Background: EDC Coverage of technique



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End Goal: Identify optimizations that guarantee error resilience



Performance resilience trade off space

Outline

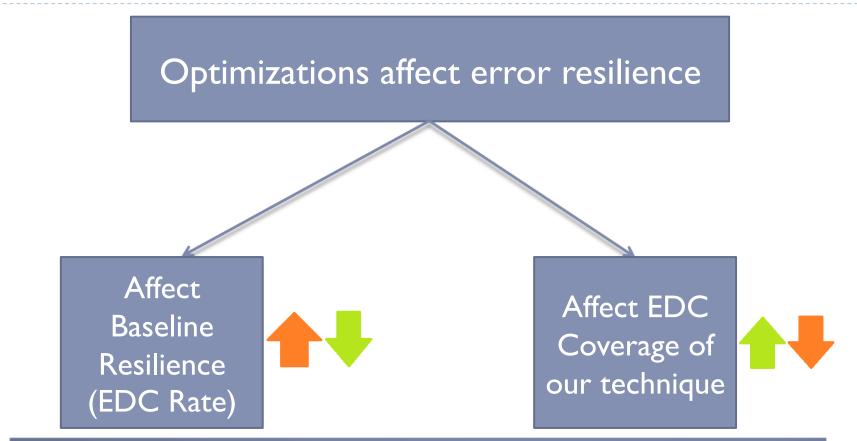
Background

Problem and Approach

Experimental Setup and Results

Conclusion

Problem



How do optimizations affect the error resilience of soft computing applications, with our technique ?

Approach

>Identified common compiler optimizations

Performed fault injections on unoptimized and optimized versions of soft computing apps

> Studied the effect of optimizations:

- > Baseline resilience
- > EDC coverage of our technique

> Identified four optimizations in LLVM compiler (of 15)

- InstCombine
- > LICM
- Loop Unroll
- > SCCP

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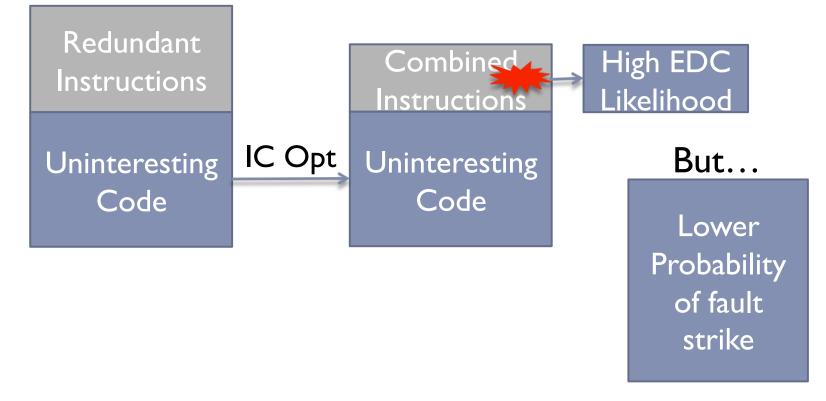
- InstCombine
- > LICM
- Loop Unroll
- > SCCP

> Why these optimizations ?

> Have conflicting effects on EDC rate



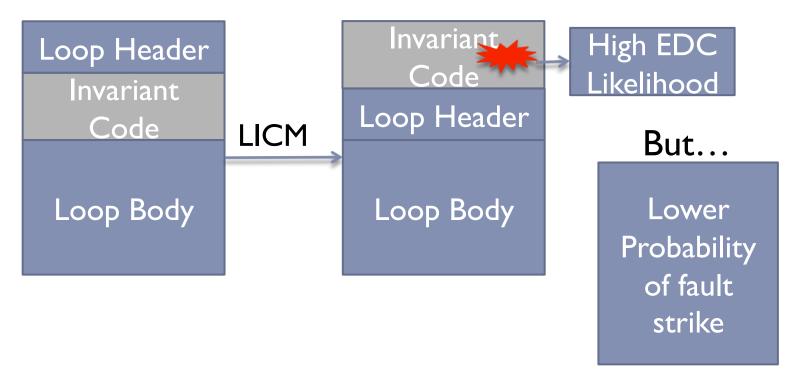
Combine Redundant Instructions: Inst-Combine



Conflicting effect on EDC rate!

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Loop Invariant Code Motion: LICM



Conflicting effect on EDC rate!



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Experimental Setup

Six Benchmarks from MediaBench and Parsec Suite

- Fidelity Metric: PSNR, scaled distortion [Misailovic I 2]
- EDC thresholds based on visual perception or 30% of SDCs

Performed fault injections using LLFI [Thomas 13]
5000 fault injections per benchmark per optimization
Error Bars: (± 0.8% at 95% CI)

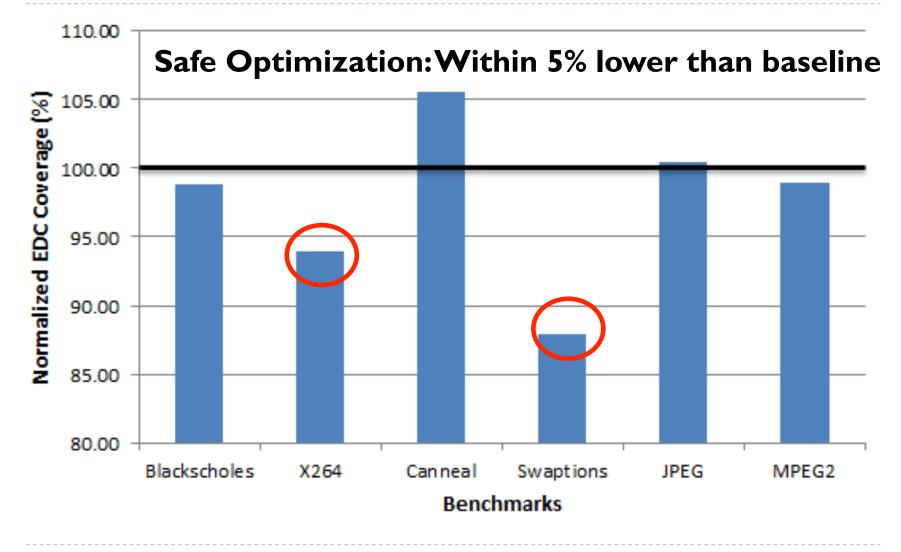
Measured coverage under 20% performance overhead
Coverage = (No of EDCs detected / total no of EDCs)*100

Baseline Resilience: EDC Percentages

Bench- mark	Inst- Combine	LICM	Loop- Unroll	SCCP	UnOpt
Blackscholes	9.9	9.48	8.48	9.38	10
X264	2.48	2.96	2.82	2.1	2.24
Canneal	4.56	3.26	3.26	3.94	3.32
Swaptions	2.5	3.12	2.44	2.98	2.36
JPEG	3.68	3.56	4.16	4.08	3.76
MPEG2	2	2.1	2.56	1.7	2.3
Average	4.19	4.08	3.95	4.03	3.99

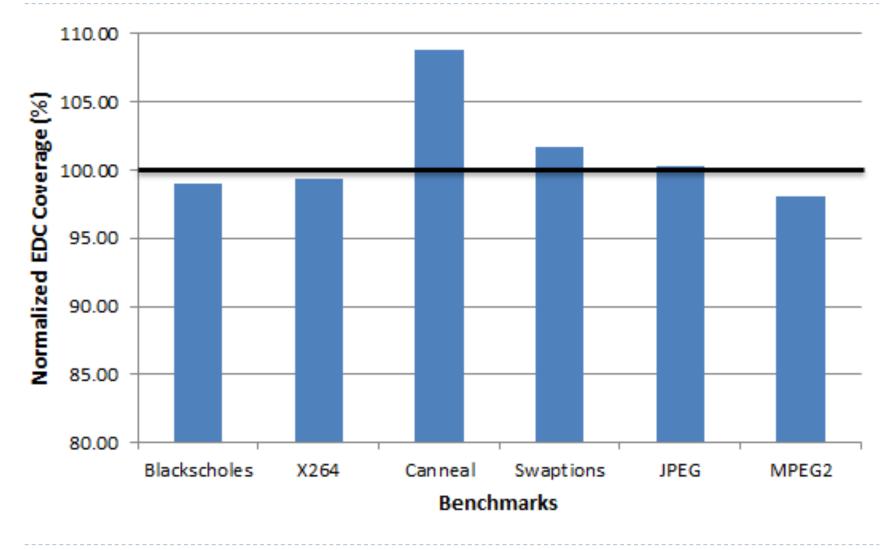
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EDC Coverage: InstCombine



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EDC Coverage: LICM



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Conclusion and Future Work

- Compiler optimizations: Characterize performanceresilience trade off in soft computing applications
 - > Baseline resilience lowered in some benchmarks
 - > Our technique preserves resilience in most cases

Future Work

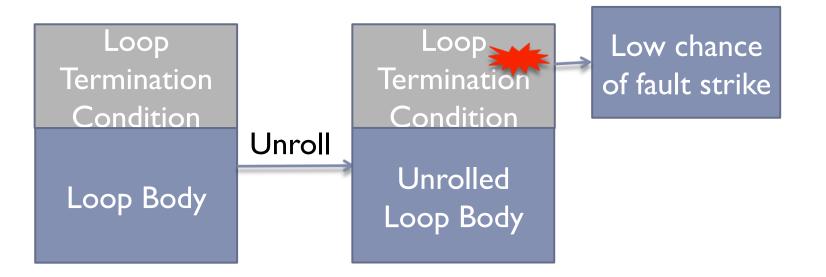
- Include more optimizations ongoing work
- Classify optimizations into resilience packages
- Decision tree for applying optimizations

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Backup Slides

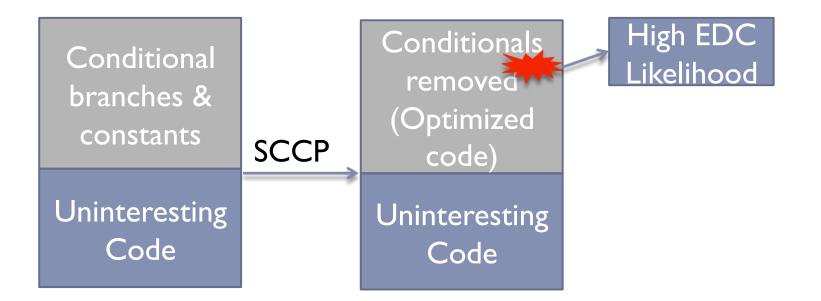


Loop Unrolling: Loop-Unroll



Lower EDC rate on Loop-Unrolled Code?

Sparse Conditional Constant Propagation: SCCP



Higher EDC rate on SCCP optimized Code?

LLVM Fault Injector LLFI

LLFI: Fault Injector at LLVM compiler's intermediate code level [Thomas'13]

